

PXP-100BPCI Express Test Platform

PXP-100B PCI Express Test Platform 16x2.5GT/s / 16x5.0 GT/s 10x1°GGL\8 \ 19x2°0 GL\8 bCI Exbrase 16x1 bisfolium bCI Exbrase 16x1 bisfolium bCI Exbrase 16x1 bisfolium

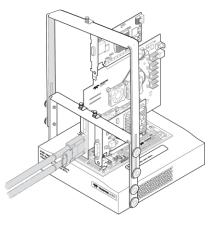
Key Features

- Provides a passive PCle® backplane for test applications
- Self-contained, portable and selfpowered
- Supplies power for +3.3V, +3.3V_{aux} and +12V rails
- Generates PCIe reference clock
- · Accepts external clock inputs
- Generates valid PERST# bus reset that can be activated by manual push button
- Includes two mid-bus probe footprints for traffic monitoring
- Supports two PCle x16 sockets which accept cards of any link width (x1, x4, x8, x16)
- Provides indication of valid connection of PRSNT1# and PRSNT2# lines for each card
- Supports data rates of 2.5 GT/s and 5.0 GT/s

The Teledyne LeCroy PXP-100B Test Platform provides a convenient means for testing PCle cards with a self-contained portable and powered passive

backplane. The PXP-100B provides power required for both cards under test, and an interposer can be used for connection to a protocol analyzer. As an alternative to an interposer, the PXP-100B includes two mid-bus footprints to allow connection to an analyzer via a mid-bus probe.

Full-featured, convenient and portable, the PXP-100B simplifies the experimental setup during testing of new PCIe products.



PXP-100B shown fully assembled, with interposer, analyzer cable, two PCIe cards and support brackets



Ordering Information

Product Description

Test platform providing two (2) PCIe G2 x16 slots, two (2) mid-bus footprints, one (1) reference clock and one (1) reset push button. [Not for 8.0 GT/s applications and beyond.]

Product Code PXP-100B-X



Local sales offices are located throughout the world. Visit our website to find the most convenient location.

1-800-5-LeCroy • teledynelecroy.com

